

# Lateral Instability in Nanoimprinted Polymer Structures

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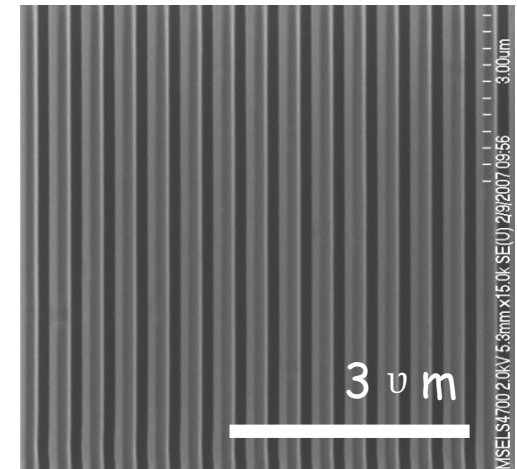
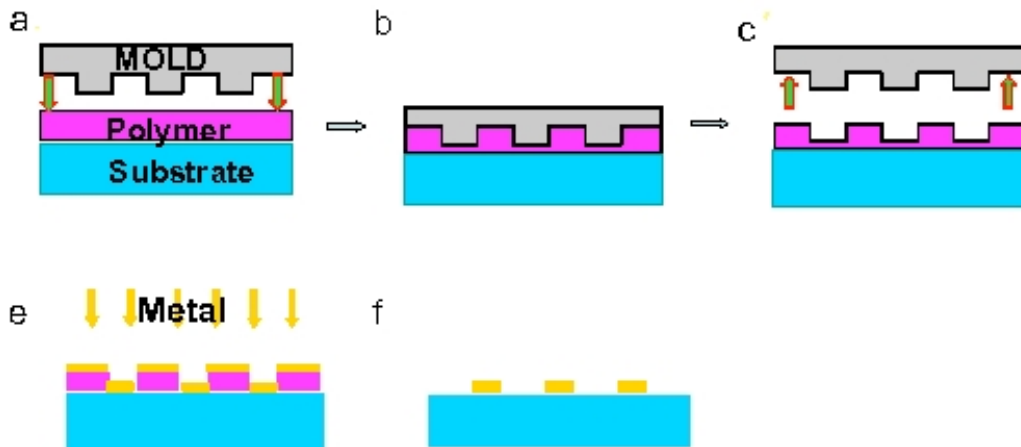
Joe Strzalka, Alec Sandy APS, Argonne National Lab

# Nanoimprint Lithography(NIL)

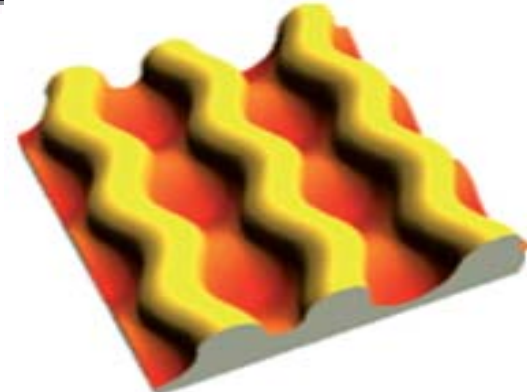
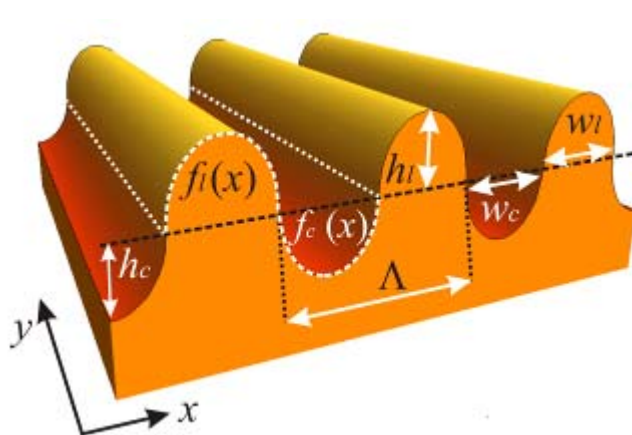
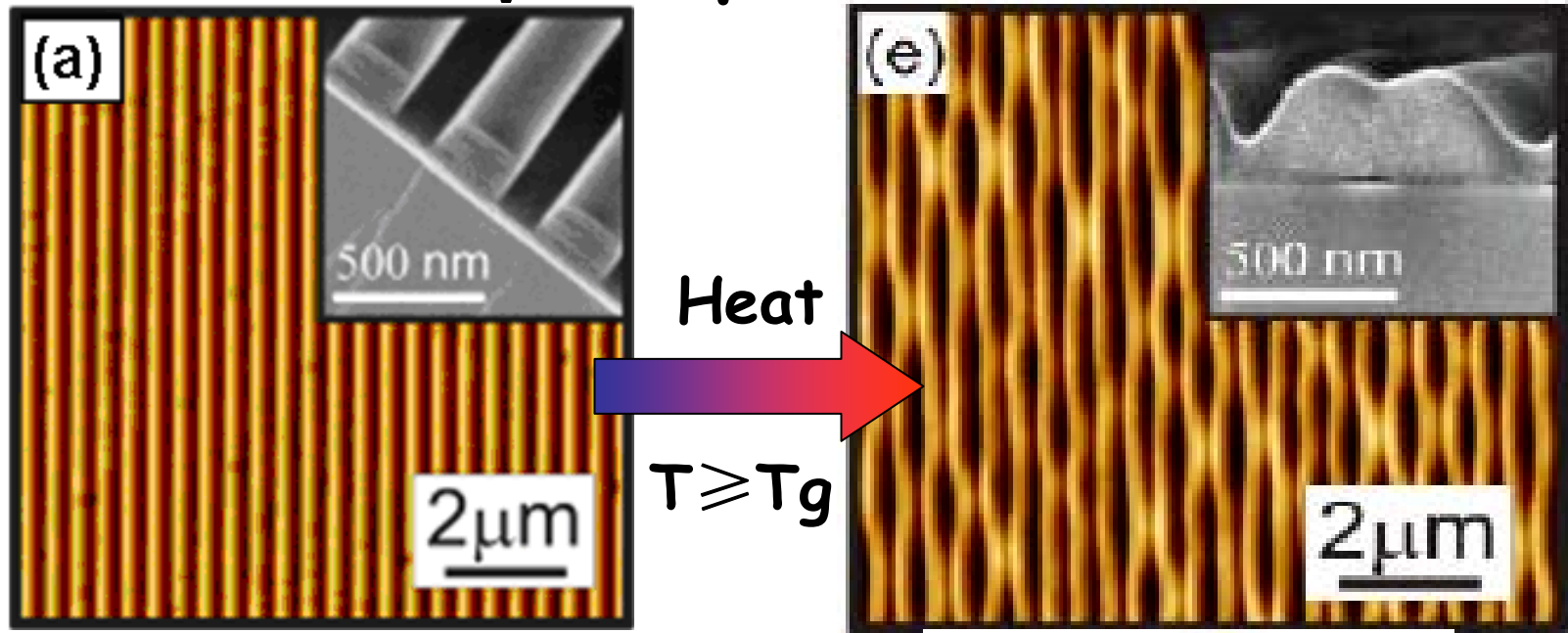
- Nanoscale pattern (metals, semiconductors...)
- Advantages: low cost, high throughput and high resolution (below 10nm)
- Challenges:

mold release

thermal stability of the polymer pattern



# Development of the zigzag instability in polymer pattern

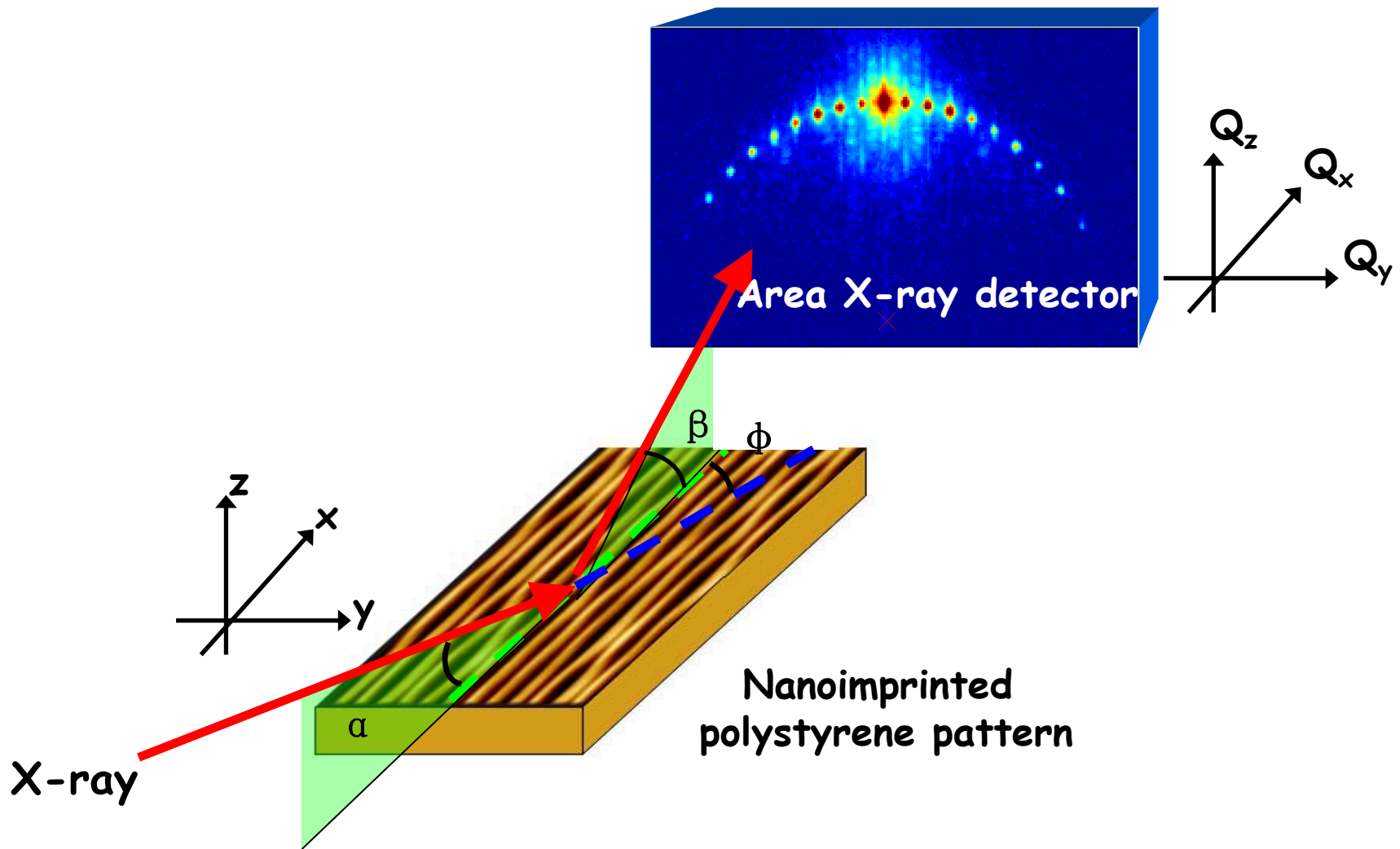


# AFM vs. GISAXS

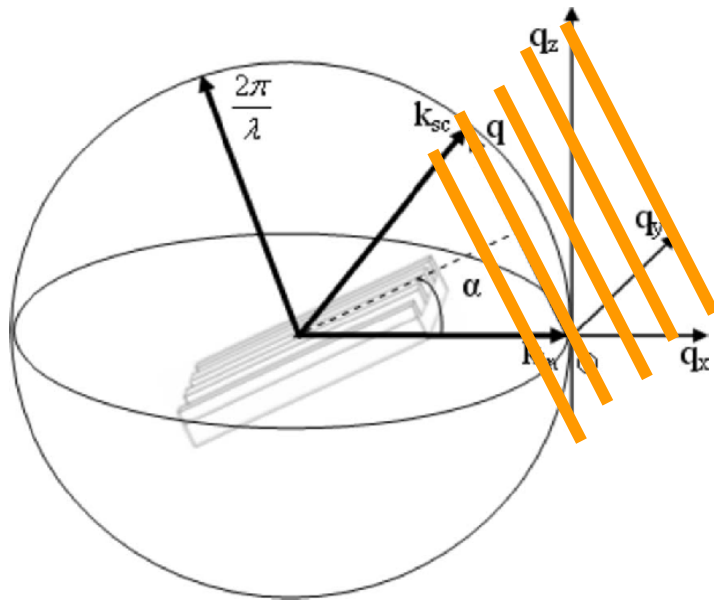
Time-resolved Grazing-Incidence  
Small-Angle X-ray Scattering

	pros	cons
<b>Local Probe</b> In-situ AFM	time resolved High resolution, real space, 3D	temporal resolution (10~100s) (or field of view) May disrupt the sample, Drift
GISAXS <b>Global Probe</b>	high time resolution (10 ms -100 s ) Global average of sample	Quantitative results can only be achieved by the application of a suitable model

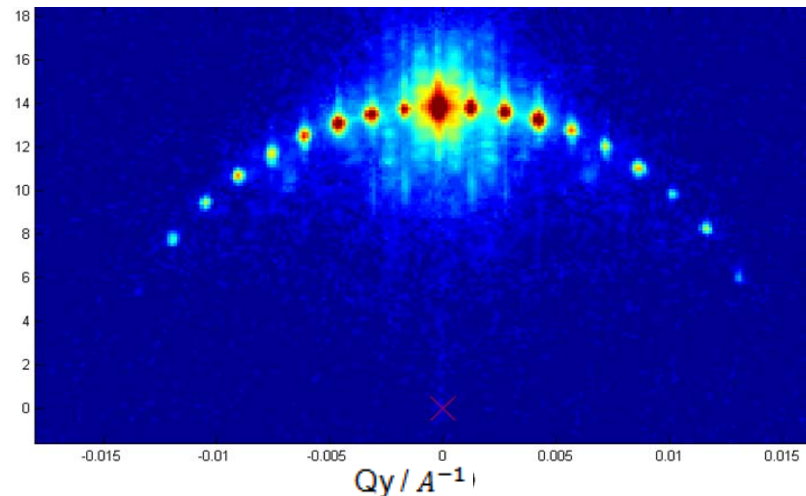
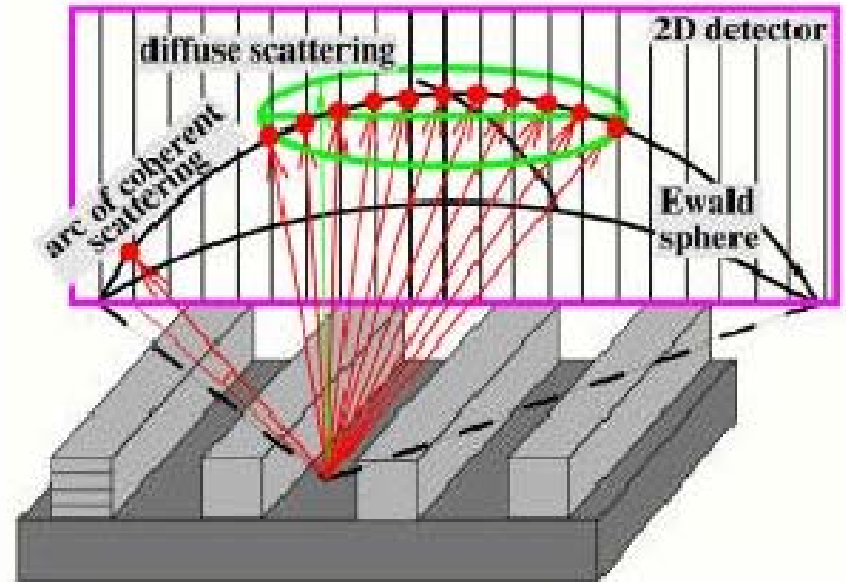
# Experiment setup at APS sector 8



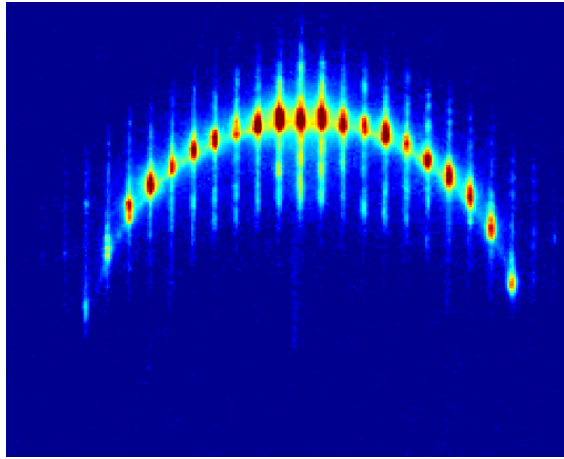
# Diffraction Pattern Geometry




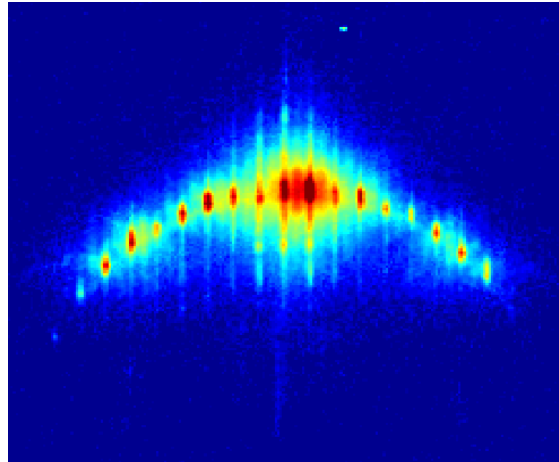
Schematic representation of the Ewald sphere and of the reciprocal space.



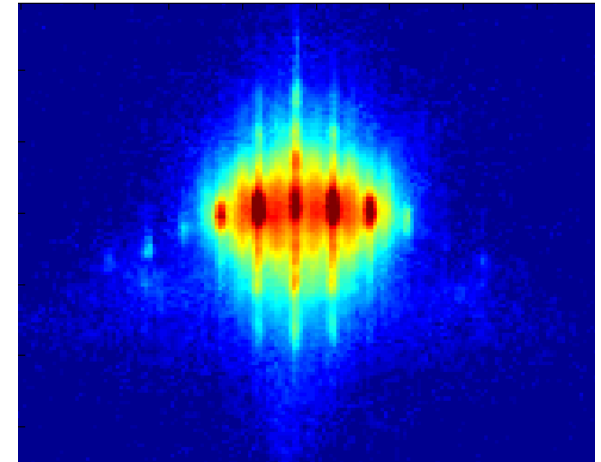
# Thermal Decay of Nanoimprinted Patterns



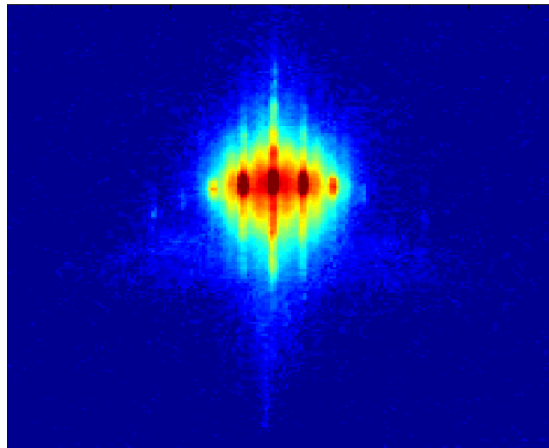
M1A#2 @  $T_g+20$  



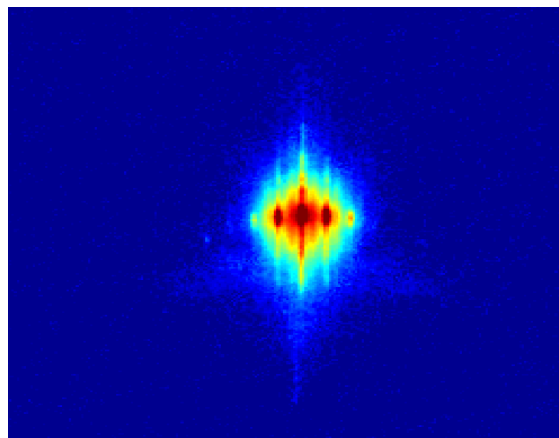
~ 2 min



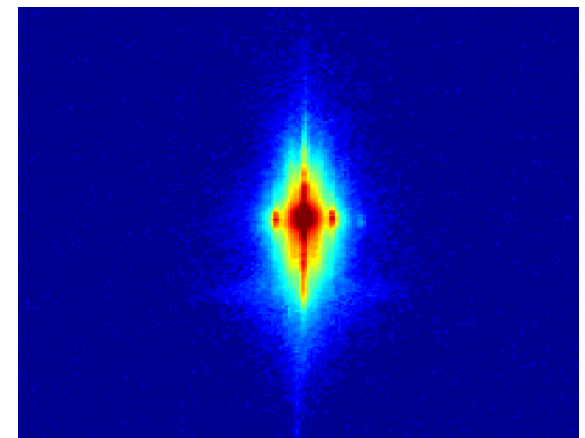
~ 3.5 min



~ 7.5 min



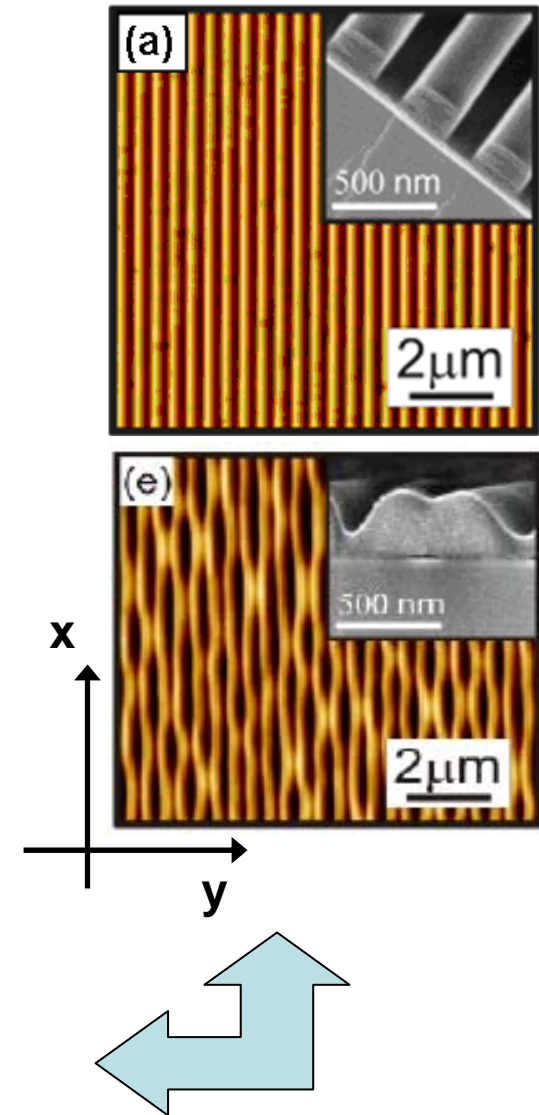
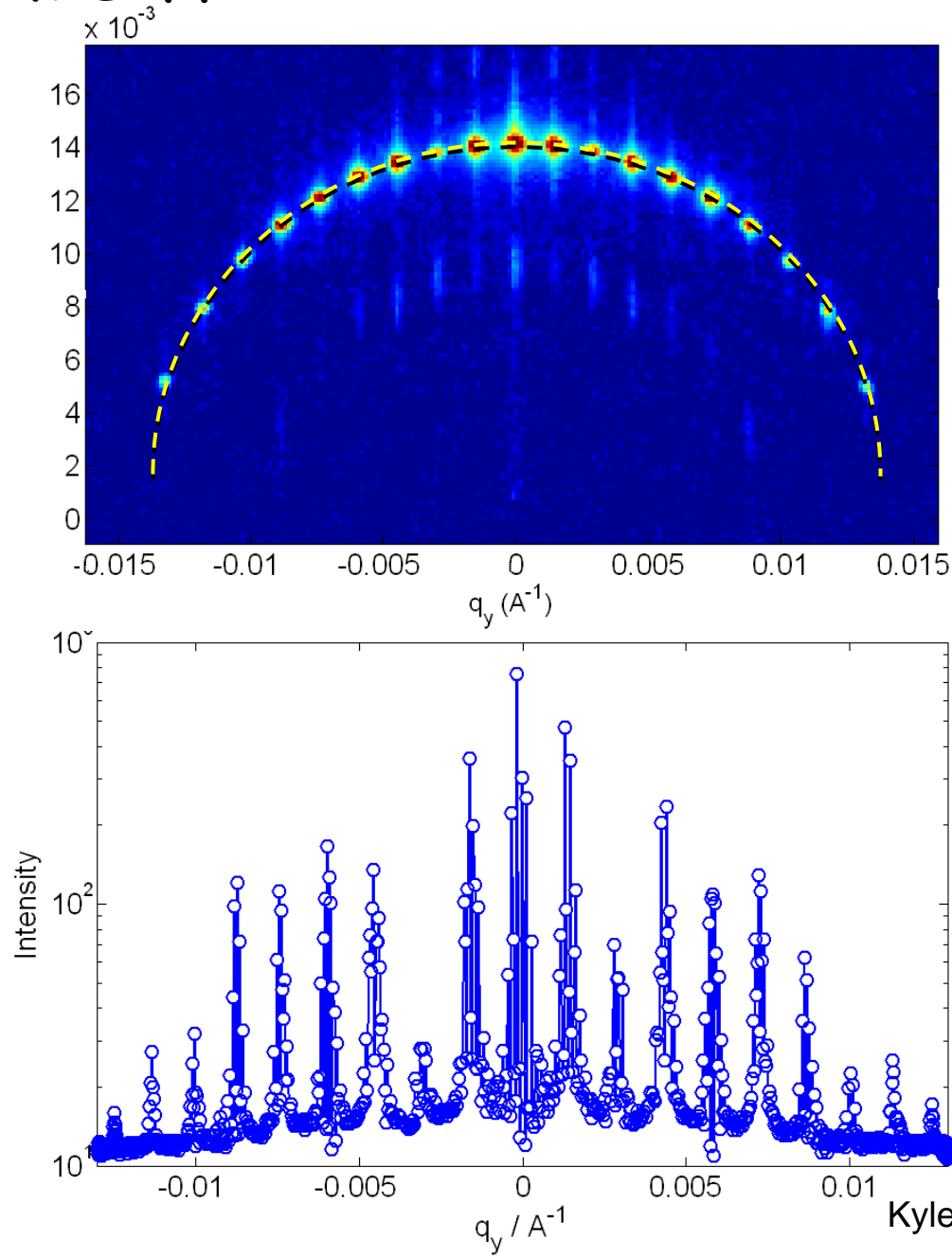
~ 11 min



~ 30.5 min

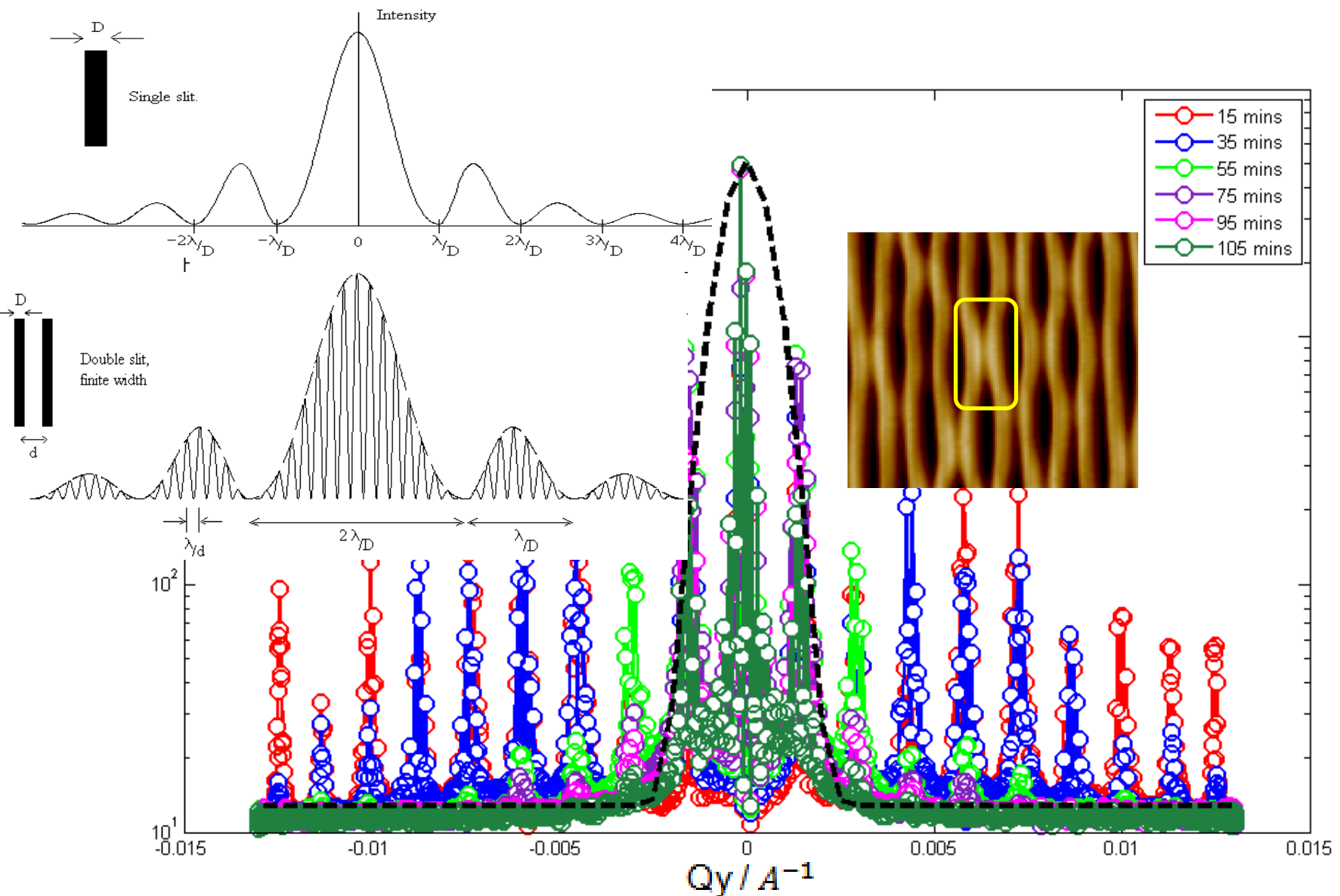


# From Diffraction intensities to real-space

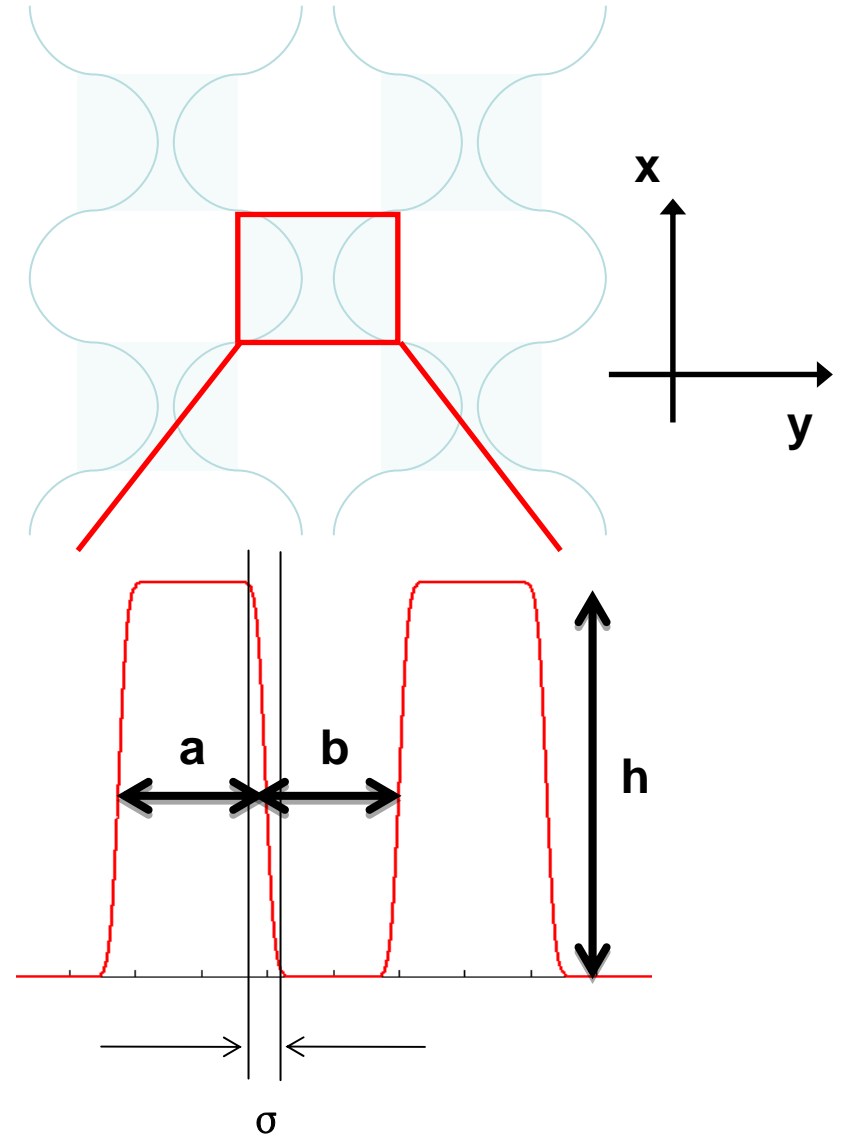
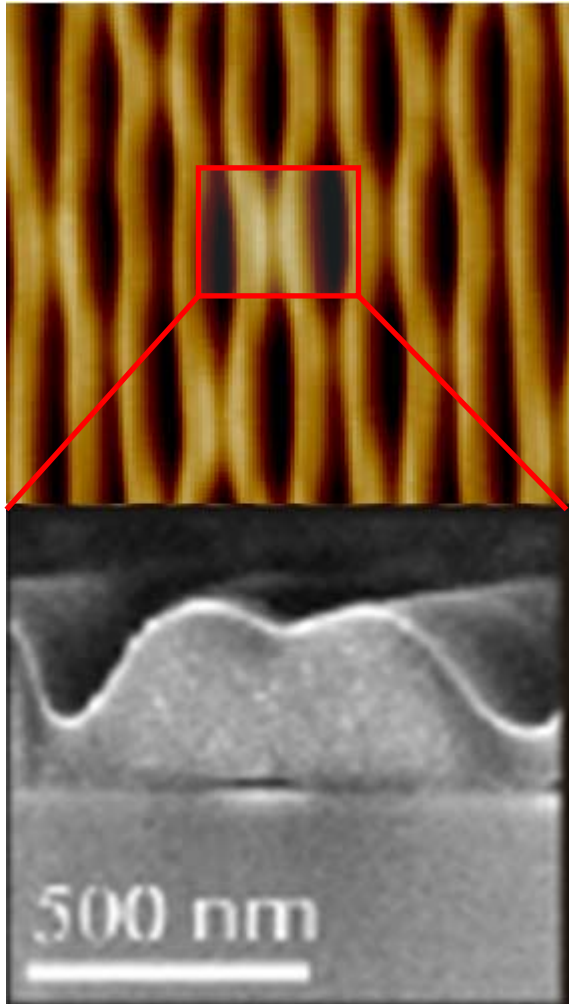




# Analysis of the Form Factor based on Zigzag Unit Cell Model



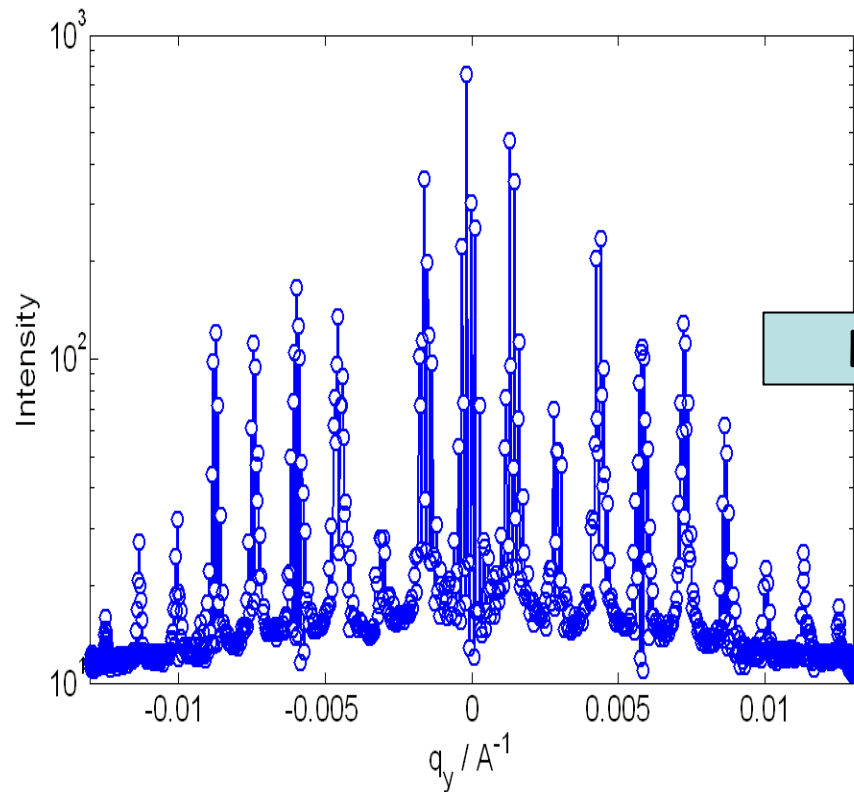
# Zigzag unit cell and Two-lines model



# Patterson Function

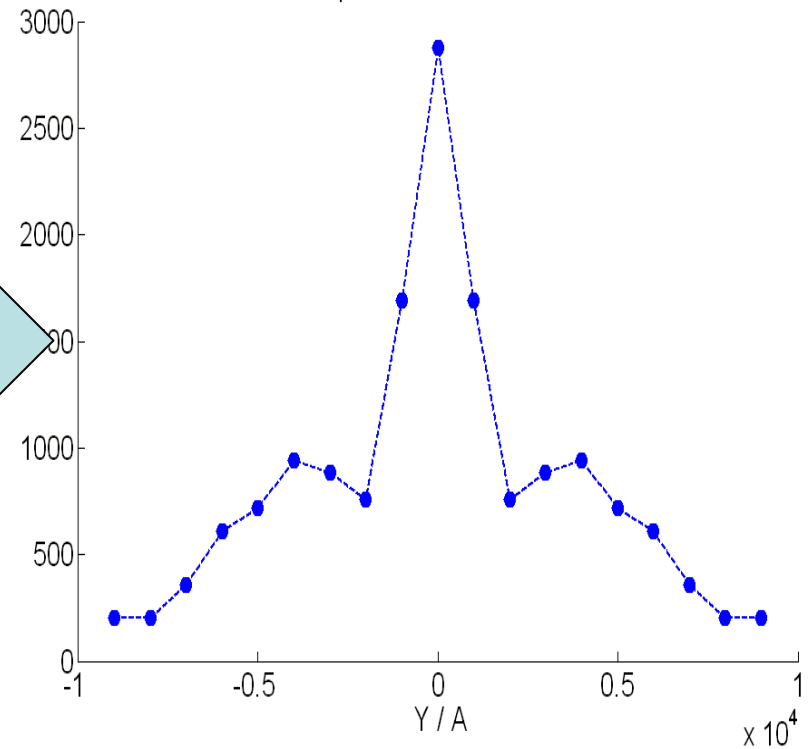
equivalent to the structure profile convolved  
with its inverse:

$$P(y) = \text{FFT}(I(qy)) = H(y) \otimes H(-y)$$

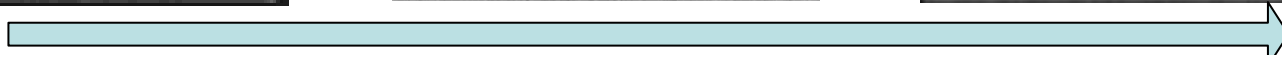
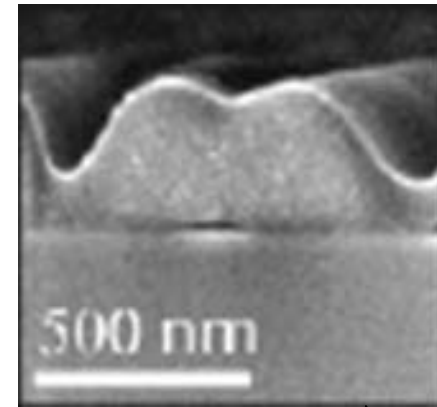
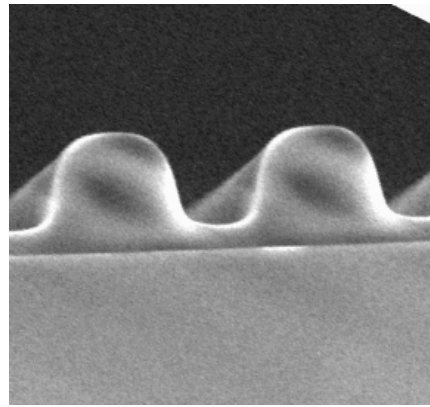
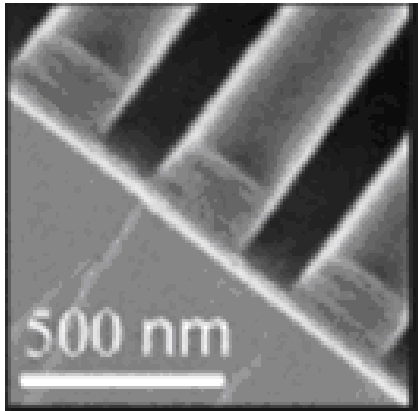


FFT

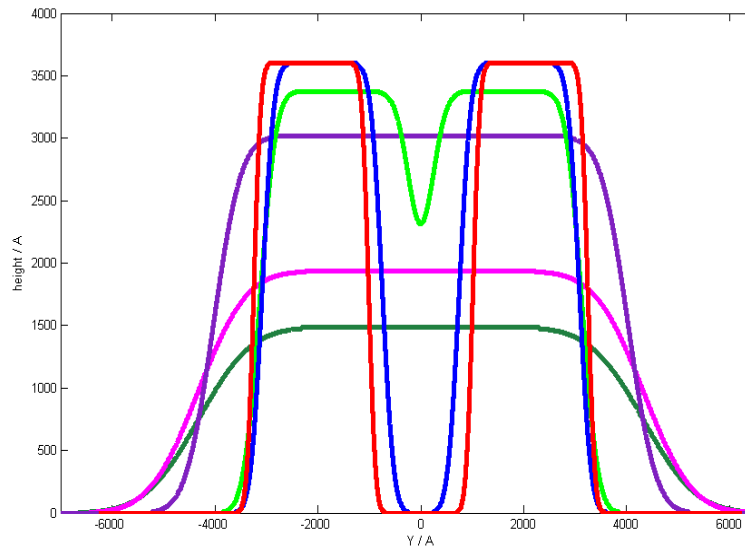
Patterson Function



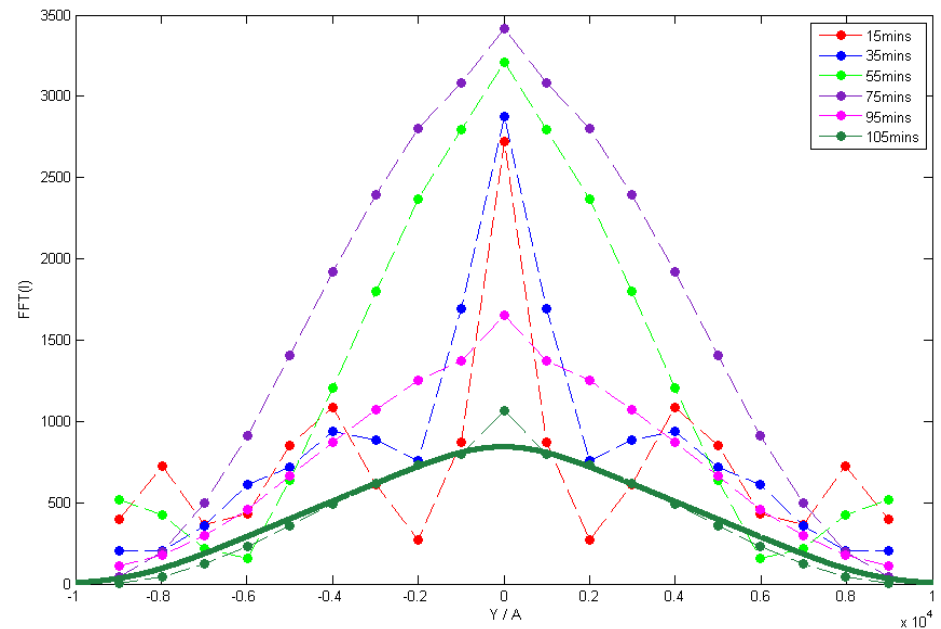
# Evolution of Lateral Structure



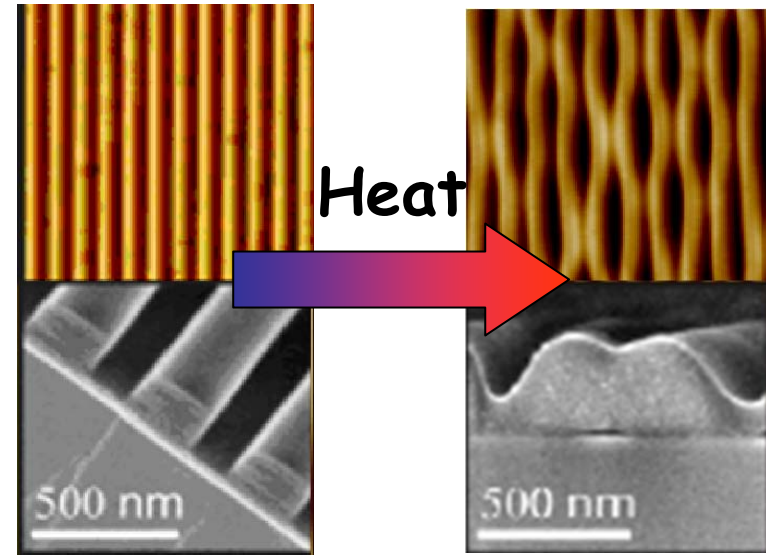
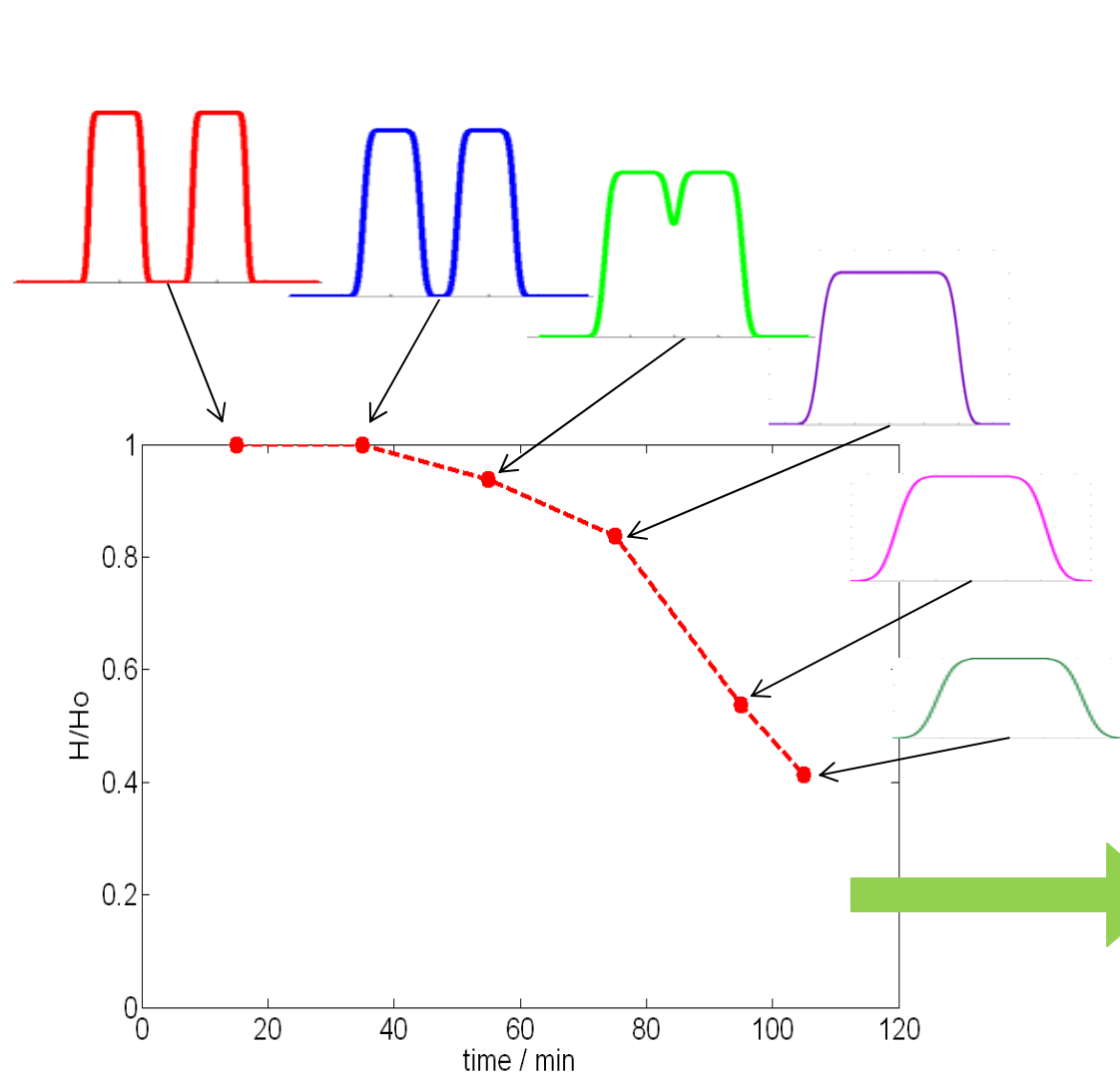
## Patterson function



Lateral structure



# Thermal instability → surface energy reduction



Will continue with  
exponential height  
decay to lower surface  
energy

# Summary

- GISAXS gives us time resolved, almost instant, high-resolution profile of coalescence unit cell.
- Complimentary information is confirmed by local probe, such as AFM.
- Both technique shows that the instability proceeds through zig-zag undulation /coalescence of lines first, followed by pattern height decay to flat film later.



## Collaboration:

- Yeling Dai, Oleg Shpyrko  
(University of California, San Diego)
- Hyun Wook Ro, Christopher Soles  
(National Institute of Standards and Technology)
- Kyle Alvine (Pacific Northwest National Lab)
- Joe Strzalka, Alec Sandy (Argonne National Lab)





Thanks!

Questions?